

Notice of Allowability

Application No.

10/729,457

Examiner

Linh M. Nguyen

Applicant(s)

ARAI, MINARI

Art Unit

2816

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to application filed 12/05/2003.
2. ☒ The allowed claim(s) is/are 1-4.
3. ☒ The drawings filed on 05 December 2003 are accepted by the Examiner.
4. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☒ All b) ☐ Some* c) ☐ None of the:
 1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).
 - * Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☒ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☒ Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date 12/05/03
4. ☐ Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413),
Paper No./Mail Date _____.
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____.

DETAILED ACTION

Claims 1-4 are currently presented in the instant application according to the Applicant's filing on 12/05/2003.

Allowable Subject Matter

1. Claims 1-4 are allowed.

Reasons for Allowance

2. The following is an examiner's statement of reasons for allowance:

The closest prior art fails to disclose or fairly suggest:

- A semiconductor integrated circuit device including a skew-comparing circuit which compares a signal transmitted from an oscillating circuit and passing through an actual input circuit and an actual output circuit, to a signal transmitted from the oscillating circuit and passing through a replica input circuit and a replica output circuit to detect a delay error between the actual input and output circuits and the replica input and output circuits, in which delays in the replica input and output circuits are compensated for in accordance with the delay error detected by the skew-comparing circuit, in combination with the remaining claimed limitations, as called for in independent claim 1;

- A semiconductor integrated circuit device including a skew-comparing circuit which compares a signal transmitted from an oscillating circuit and passing through an actual output circuit, to a signal transmitted from the oscillating circuit and passing through a replica output circuit to detect a delay error between the actual output circuit and the replica output circuit, in which delay in the replica output circuit is compensated for in accordance with the delay error

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detected by the skew-comparing circuit, in combination with the remaining claimed limitations, as called for in independent claim 2;

- A method of detecting a delay error between actual input and output circuits and replica input and output circuits, including the steps of (a) having a reference signal passed through the actual input and output circuits (b) having the reference signal passed through the replica input and output circuits; and (c) comparing the reference signal in the step (a) to the reference signal in the step (b) to detect the delay error, in combination with the remaining claimed limitations, as called for in independent claim 3; and

- A method of detecting a delay error between actual input and output circuits and replica input and output circuits, including the steps of (a) having a reference signal passed through the actual output circuit; (b) having the reference signal passed through the replica output circuit; and (c) comparing the reference signal in the step (a) to the reference signal in the step (b) to detect a delay error between the actual output circuit and the replica output circuit, in combination with the remaining claimed limitations, as called for in independent claim 4.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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Inquiry

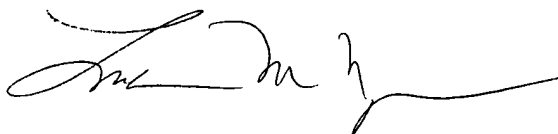
Any inquiry concerning this communication or earlier communications from the examiner should be directed to Linh M. Nguyen whose telephone number is (571) 272-1749. The examiner can normally be reached on Alternate Fri, Monday - Thursday from 7:00 to 4:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Timothy P. Callahan can be reached on (571) 272-1740. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Linh M. Nguyen
Primary Examiner
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LMN

A handwritten signature in black ink, appearing to read 'Linh M. Nguyen', with a long horizontal flourish extending to the right.